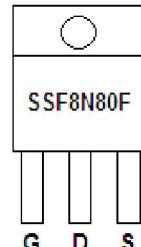


### Main Product Characteristics

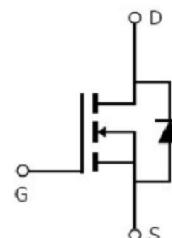
|              |             |
|--------------|-------------|
| $V_{DSS}$    | 800V        |
| $R_{DS(on)}$ | 1.3Ω (typ.) |
| $I_D$        | 8A          |



TO220F



Marking and Pin Assignment



Schematic Diagram Assignment

### Features and Benefits

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature
- Lead free product



### Description

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

### Absolute Max Rating

| Symbol                      | Parameter  | Max.        | Units         |
|-----------------------------|--|-------------|---------------|
| $I_D$ @ $T_C = 25^\circ C$  | Continuous Drain Current, $V_{GS} @ 10V$ ①       | 8           | A             |
| $I_D$ @ $T_C = 100^\circ C$ | Continuous Drain Current, $V_{GS} @ 10V$ ①       | 5.1         |               |
| $I_{DM}$                    | Pulsed Drain Current②                            | 32          |               |
| $P_D$ @ $T_C = 25^\circ C$  | Power Dissipation③                               | 59          | W             |
|                             | Linear Derating Factor                           | 0.48        | W/ $^\circ C$ |
| $V_{DS}$                    | Drain-Source Voltage                             | 800         | V             |
| $V_{GS}$                    | Gate-to-Source Voltage                           | $\pm 30$    | V             |
| $E_{AS}$                    | Single Pulse Avalanche Energy @ $L=25mH$         | 760         | mJ            |
| $I_{AS}$                    | Avalanche Current @ $L=25mH$                     | 7.8         | A             |
| $T_J$ $T_{STG}$             | Operating Junction and Storage Temperature Range | -55 to +150 | $^\circ C$    |



## Thermal Resistance

| Symbol           | Characteristics                              | Typ. | Max. | Units |
|------------------|--|------|------|-------|
| R <sub>θJC</sub> | Junction-to-case <sup>(3)</sup>              | —    | 2.1  | °C/W  |
| R <sub>θJA</sub> | Junction-to-ambient (t ≤ 10s) <sup>(4)</sup> | —    | 62.5 | °C/W  |

## Electrical Characteristics @T<sub>A</sub>=25°C unless otherwise specified

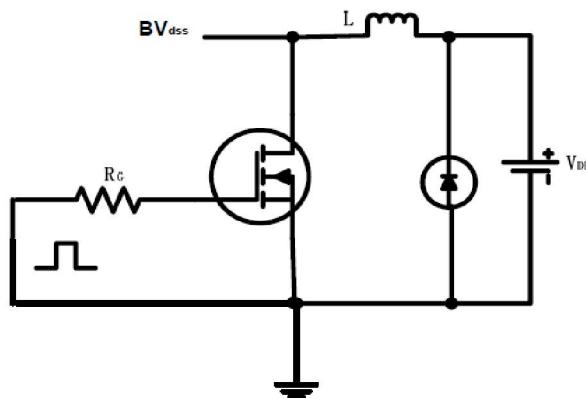
| Symbol               | Parameter                            | Min. | Typ. | Max. | Units | Conditions  |
|----------------------|--------------------------------------|------|------|------|-------|---|
| V <sub>(BR)DSS</sub> | Drain-to-Source breakdown voltage    | 800  | —    | —    | V     | V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA  |
| R <sub>DS(on)</sub>  | Static Drain-to-Source on-resistance | —    | 1.3  | 1.55 | Ω     | V <sub>GS</sub> =10V, I <sub>D</sub> = 3.5A   |
|                      |                                      | —    | 3.07 | —    |       | T <sub>J</sub> = 125°C  |
| V <sub>GS(th)</sub>  | Gate threshold voltage               | 2    | —    | 4    | V     | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA  |
|                      |                                      | —    | 1.93 | —    |       | T <sub>J</sub> = 125°C  |
| I <sub>DSS</sub>     | Drain-to-Source leakage current      | —    | —    | 1    | μA    | V <sub>DS</sub> = 800V, V <sub>GS</sub> = 0V  |
|                      |                                      | —    | —    | 50   |       | T <sub>J</sub> = 125°C  |
| I <sub>GSS</sub>     | Gate-to-Source forward leakage       | —    | —    | 100  | nA    | V <sub>GS</sub> = 30V   |
|                      |                                      | —    | —    | -100 |       | V <sub>GS</sub> = -30V  |
| Q <sub>g</sub>       | Total gate charge                    | —    | 24   | —    | nC    | I <sub>D</sub> = 8A,  |
| Q <sub>gs</sub>      | Gate-to-Source charge                | —    | 7.2  | —    |       | V <sub>DS</sub> = 400V,   |
| Q <sub>gd</sub>      | Gate-to-Drain("Miller") charge       | —    | 9.7  | —    |       | V <sub>GS</sub> = 10V   |
| t <sub>d(on)</sub>   | Turn-on delay time                   | —    | 20   | —    |       |   |
| t <sub>r</sub>       | Rise time                            | —    | 37   | —    | ns    | V <sub>GS</sub> =10V, V <sub>DS</sub> =400V,<br>R <sub>L</sub> =50Ω, R <sub>GEN</sub> =25Ω<br>ID=8A |
| t <sub>d(off)</sub>  | Turn-Off delay time                  | —    | 59   | —    |       |   |
| t <sub>f</sub>       | Fall time                            | —    | 36   | —    |       |   |
| C <sub>iss</sub>     | Input capacitance                    | —    | 1106 | —    | pF    | V <sub>GS</sub> = 0V  |
| C <sub>oss</sub>     | Output capacitance                   | —    | 121  | —    |       | V <sub>DS</sub> = 25V   |
| C <sub>rss</sub>     | Reverse transfer capacitance         | —    | 5.2  | —    |       | f = 1MHz  |

## Source-Drain Ratings and Characteristics

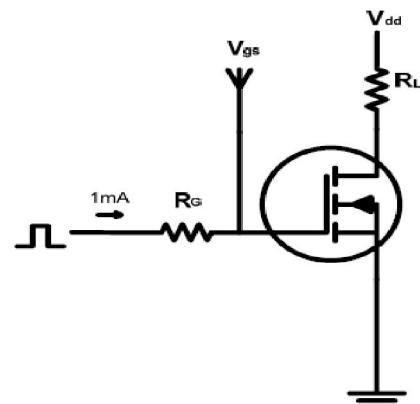
| Symbol          | Parameter                                 | Min. | Typ. | Max. | Units | Conditions   |
|-----------------|---|------|------|------|-------|--|
| I <sub>S</sub>  | Continuous Source Current<br>(Body Diode) | —    | —    | 8    | A     | MOSFET symbol showing the integral reverse p-n junction diode. |
| I <sub>SM</sub> | Pulsed Source Current<br>(Body Diode)     | —    | —    | 32   | A     |  |
| V <sub>SD</sub> | Diode Forward Voltage                     | —    | 0.74 | 1.4  | V     | I <sub>S</sub> =7A, V <sub>GS</sub> =0V                        |
| t <sub>rr</sub> | Reverse Recovery Time                     | —    | 968  | —    | ns    | T <sub>J</sub> = 25°C, I <sub>F</sub> = 8A, di/dt = 100A/μs    |
| Q <sub>rr</sub> | Reverse Recovery Charge                   | —    | 5456 | —    | nC    |  |

## Test Circuits and Waveforms

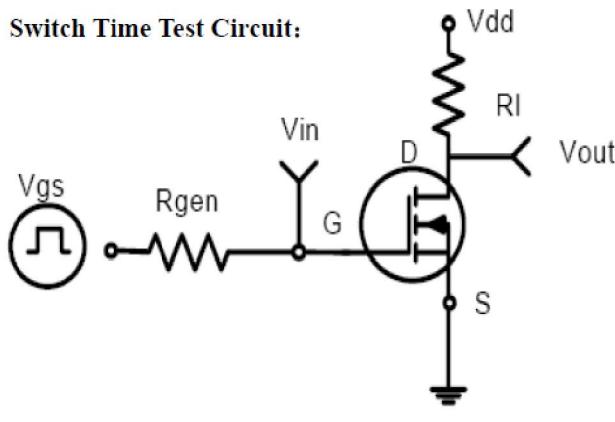
EAS test circuits:



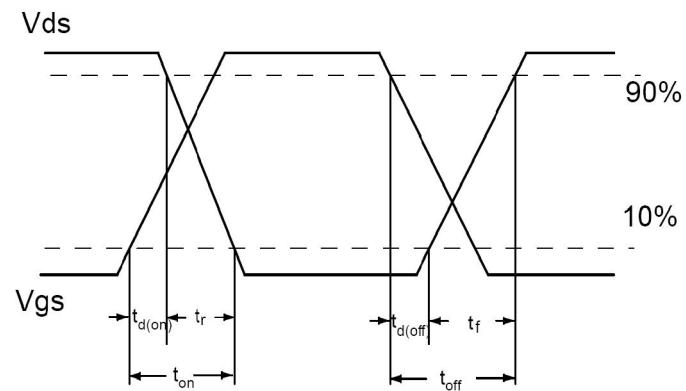
Gate charge test circuit:



Switch Time Test Circuit:



Waveforms:



## Notes:

- ① The maximum current rating is limited by bond-wires.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with  $TA = 25^\circ C$

## Typical Electrical and Thermal Characteristics

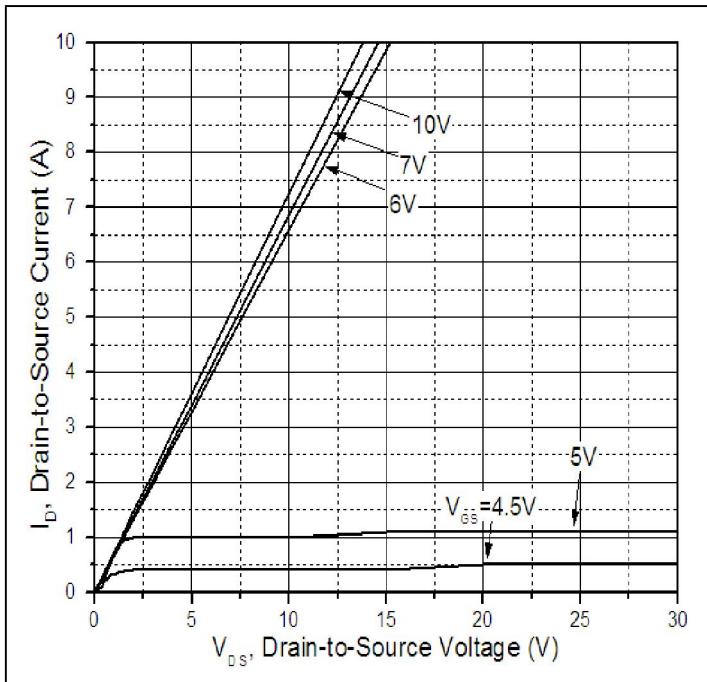


Figure 1: Typical Output Characteristics

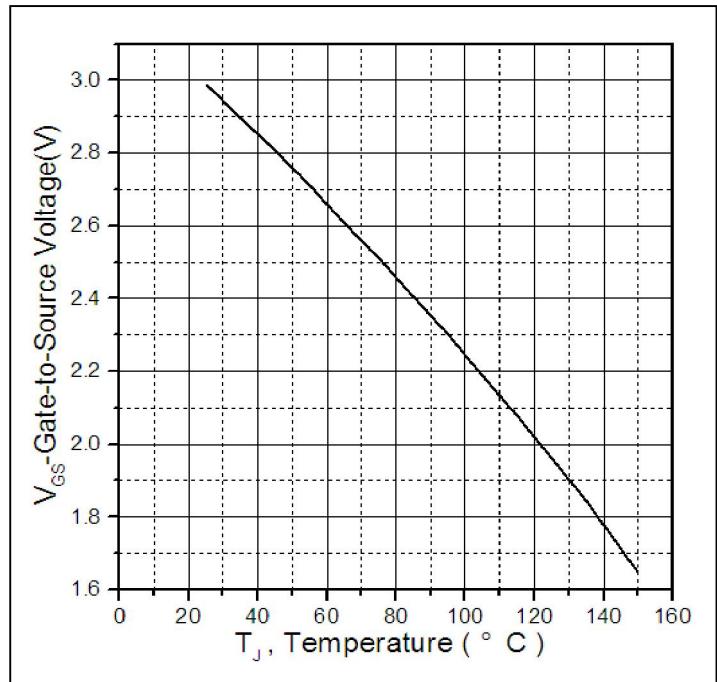


Figure 2. Gate to source cut-off voltage

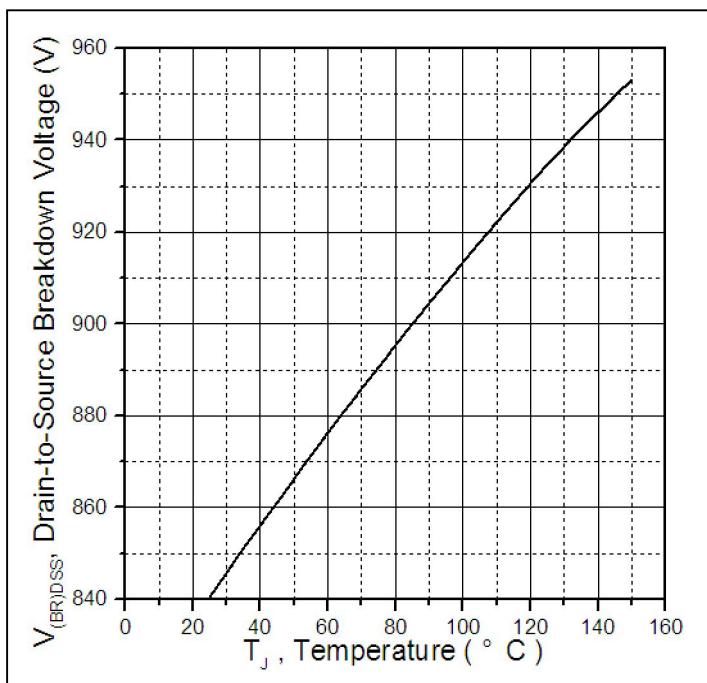


Figure 3. Drain-to-Source Breakdown Voltage Vs.  
Case Temperature

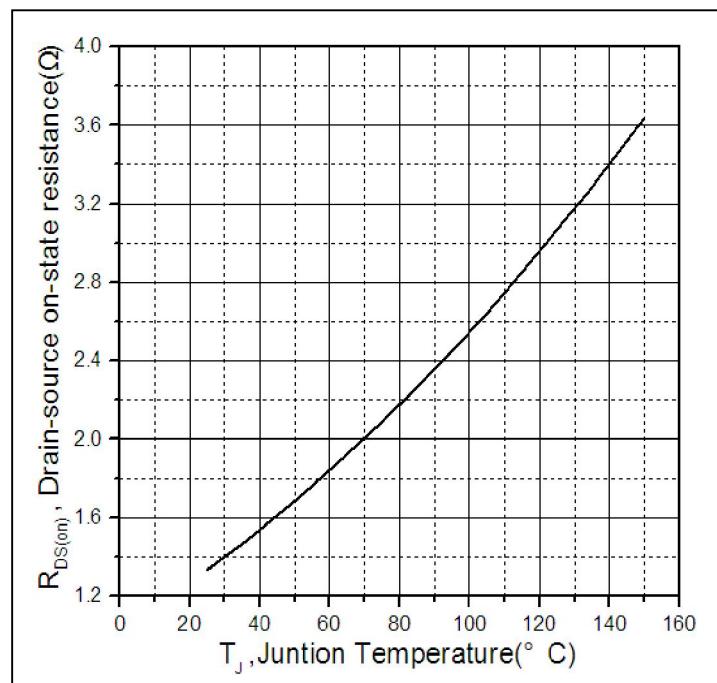


Figure 4: Normalized On-Resistance Vs. Case  
Temperature

## Typical Electrical and Thermal Characteristics

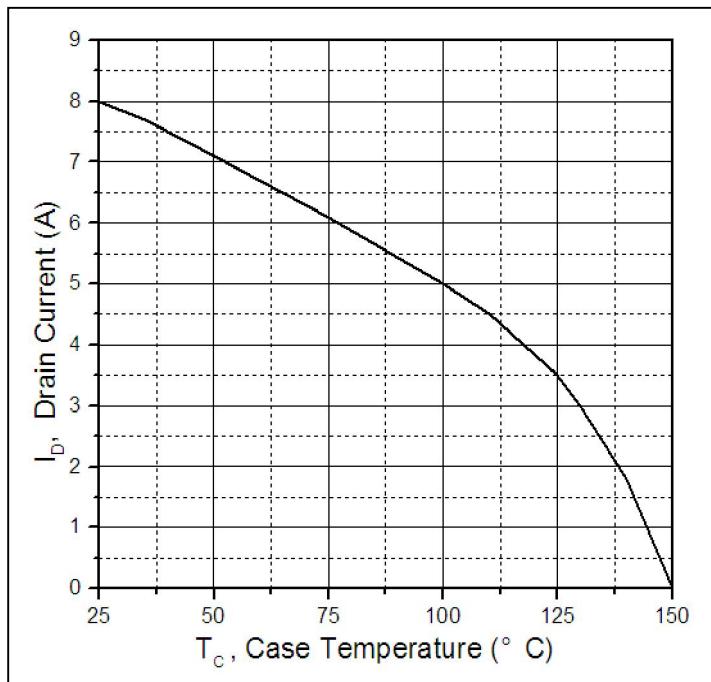


Figure 5. Maximum Drain Current Vs. Case Temperature

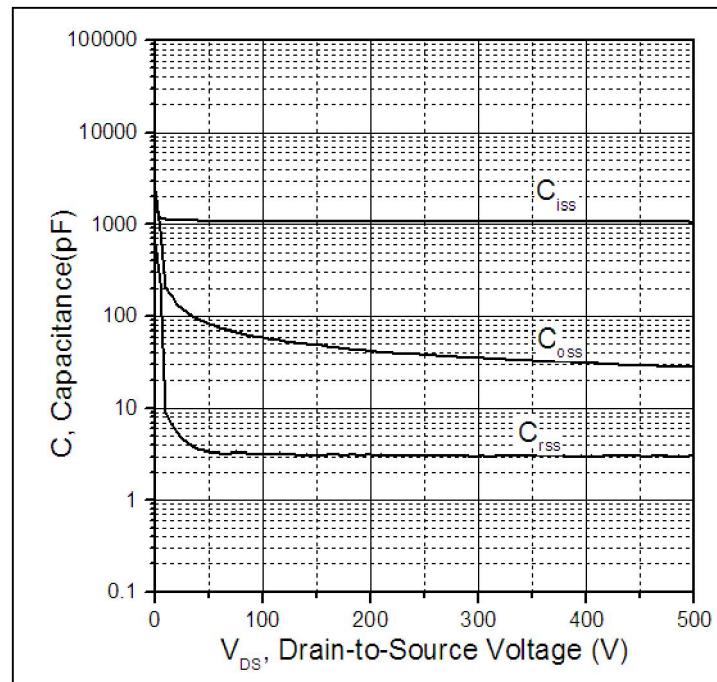


Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

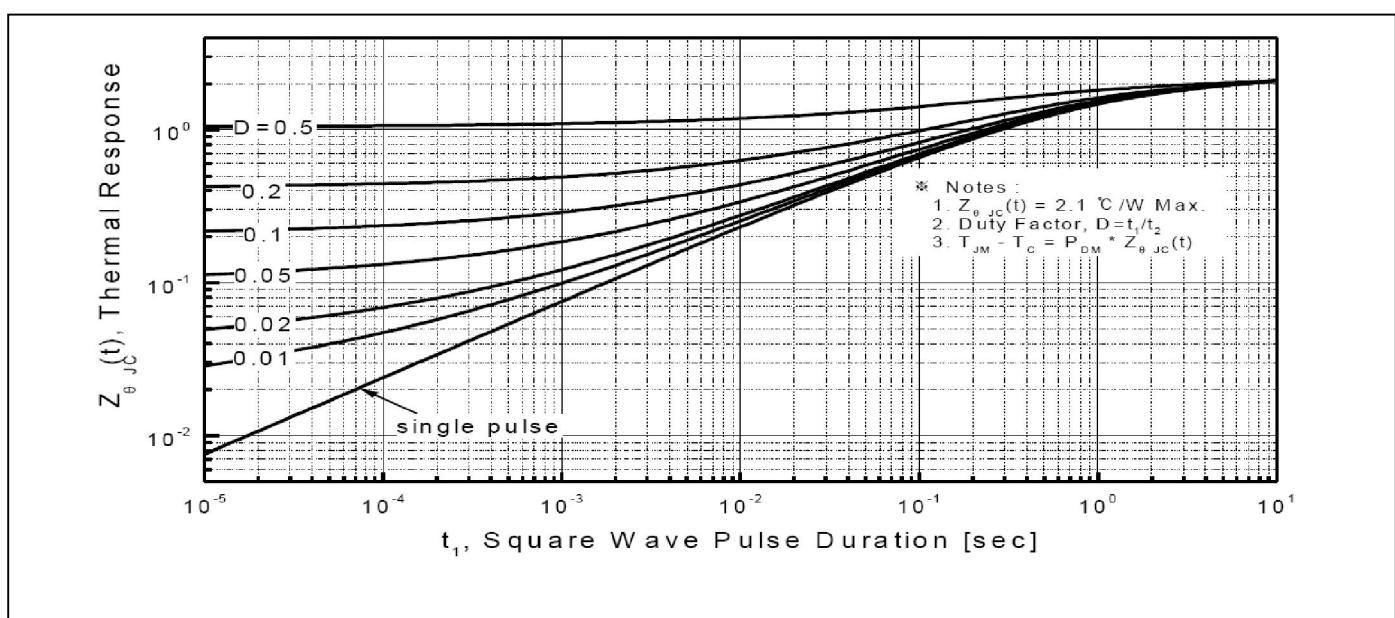
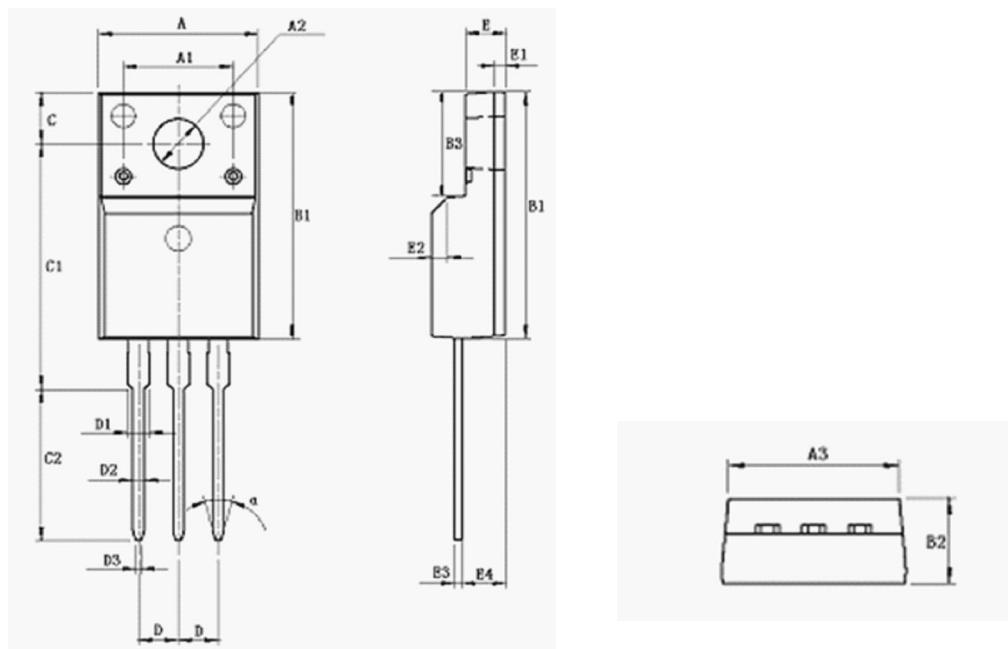


Figure7. Maximum Effective Transient Thermal Impedance, Junction-to-Case

## Mechanical Data

TO220F PACKAGE OUTLINE DIMENSION



| Symbol | Dimension In Millimeters |        |        | Dimension In Inches |       |       |
|--------|--------------------------|--------|--------|---------------------|-------|-------|
|        | Min                      | Nom    | Max    | Min                 | Nom   | Max   |
| A      | 9.960                    | 10.160 | 10.360 | 0.392               | 0.400 | 0.408 |
| A1     |                          | 7.000  |        | 0.276               | 0.000 | 0.000 |
| A2     | 3.080                    | 3.180  | 3.280  | 0.121               | 0.125 | 0.129 |
| A3     | 9.260                    | 9.460  | 9.660  | 0.365               | 0.372 | 0.380 |
| B1     | 15.670                   | 15.870 | 16.070 | 0.617               | 0.625 | 0.633 |
| B2     | 4.500                    | 4.700  | 4.900  | 0.177               | 0.185 | 0.193 |
| B3     | 6.480                    | 6.680  | 6.880  | 0.255               | 0.263 | 0.271 |
| C      | 3.200                    | 3.300  | 3.400  | 0.126               | 0.130 | 0.134 |
| C1     | 15.600                   | 15.800 | 16.000 | 0.614               | 0.622 | 0.630 |
| C2     | 9.550                    | 9.750  | 9.950  | 0.376               | 0.384 | 0.392 |
| D      | 2.54 (TYP)               |        |        | 1.00 (TYP)          |       |       |
| D1     | -                        | -      | 1.470  | -                   | -     | 0.058 |
| D2     | 0.700                    | 0.800  | 0.900  | 0.028               | 0.031 | 0.035 |
| D3     | 0.250                    | 0.350  | 0.450  | 0.010               | 0.014 | 0.018 |
| E      | 2.340                    | 2.540  | 2.740  | 0.092               | 0.100 | 0.108 |
| E1     | 0.700                    |        |        | 0.028               |       |       |
| E2     | 1.0*45°                  |        |        | 1.0*45°             |       |       |
| E3     | 0.450                    | 0.500  | 0.600  | 0.018               | 0.020 | 0.024 |
| E4     | 2.560                    | 2.760  | 2.960  | 0.101               | 0.109 | 0.117 |
| □      | 30°                      |        |        | 30°                 |       |       |



**SSF8N80F**  
800V N-Channel MOSFET

## Ordering and Marking Information

### Device Marking: SSF8N80F

Package (Available)

TO220F

Operating Temperature Range

C : -55 to 150 °C

### Devices per Unit

| Package Type | Units/Tube | Tubes/Inner Box | Units/Inner Box | Inner Boxes/Carton Box | Units/Carton Box |
|--------------|------------|-----------------|-----------------|------------------------|------------------|
| TO220F       | 50         | 20              | 1000            | 6                      | 6000             |

### Reliability Test Program

| Test Item                           | Conditions   | Duration                             | Sample Size         |
|-------------------------------------|--|--------------------------------------|---------------------|
| High Temperature Reverse Bias(HTRB) | $T_j=125^\circ\text{C}$ to $150^\circ\text{C}$ @ 80% of Max $V_{DSS}/V_{CES}/VR$ | 168 hours<br>500 hours<br>1000 hours | 3 lots x 77 devices |
| High Temperature Gate Bias(HTGB)    | $T_j=150^\circ\text{C}$ @ 100% of Max $V_{GSS}$                                  | 168 hours<br>500 hours<br>1000 hours | 3 lots x 77 devices |